## 2D binary grating

We consider 2D binary grating from paper: Song *Peng* and G. Michael *Morris. JOSA A*, Vol. 12, Issue 5, pp. 1087-1096 (1995). Parameters of the grating and calculation are following: wavelength  $\lambda$ =1 µm, thickness d=1 µm, periods  $\Lambda_x = \Lambda_y = 1.2$  µm, incident angle  $\theta$ =0°, refractive index of the incident region  $n_1$ =1, refractive index of the transmission region  $n_3$ =1.5, conical angle  $\varphi$ =0°, polarization angle  $\varphi$ =90° and 50% duty cycle (n=1.5) along the *x* and the *y* axis.

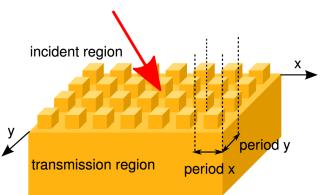


Figure 1: Definition of a crossed grating.

Grating is defined in the file peng simple dielectric grating.m (directory /structures)

```
number_of_layers=1;
l=1; % layer 1
thickness(l)=1;
coordinate_x_1=1.2.*[0,0.25,0.75,1];
coordinate_y_1=1.2.*[0,0.25,0.75,1];
r_index_1=[1, 1, 1;
    1, 1.5, 1;
    1, 1, 1];
```

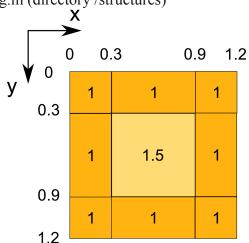


Figure 2: Discretization of a

Variable *coordinate\_x\_1* defines x-axis coordinate of the *grating*. grating (see Fig. 2), variable *coordinate\_y\_1* defines y-axis coordinate of the grating, variable  $r\_index\_1$  defines refractive index of the own grating. Rows of the matrix  $r\_index\_1$  represent refractive indicies in the x-axis direction, columns of the matrix  $r\_index\_1$  represent refractive indicies in the y-axis direction.

Next, we set others parameters in the main.m file:

```
N_X=5; % N_X=20 takes approx. 8 GB of memory

n_1=1.0; % superstrate
n_3=1.5; % substrate

lambda=1;
theta0=0; % incident angle [degree], if theta=0 -> theta0+1E-10
phi0=0; % conical angle [degree]
psi0=90; % polarization angle [degree], 0-TM polarization, 90-TE polarization

grating=0;
switch grating
    case 0
```

```
open_grating_file='peng_simple_dielectric_grating.m';
measurement=0;
diffraction_efficiency_order=[0,0];
We obtain this result:
order [ 0.00,  0.00] R_0=0.0027488206 T_0=0.2321819422 sumR=0.0172254040 sumT=0.9827745960 R_90=0.0027488206 T_90=0.2321819422 sumR=0.0172254040 sumT=0.9827745960 R_psi=0.0027488206 T_psi=0.2321819422 sumR=0.0172254040 sumT=0.9827745960
time of calculation = 2.470000e+00 s
```

This result is only for order [0,0], the first set of results are for  $\psi$ =0° (TM polarization), the second set of results are for  $\psi$ =90° (TE polarization), and the third set of results are for certain angle  $\psi$  which is defined in the file main.m. Another order (e.g. [-1,0]) can be displayed using variable another diffraction efficiency order.

```
>> another_diffraction_efficiency_order([-1,0])

order [-1.00, 0.00] R_0=0.0057446268 T_0=0.1550288046 sumR=0.0172254040 sumT=0.9827745960 R_90=0.0014936648 T_90=0.1690707065 sumR=0.0172254040 sumT=0.9827745960 R_psi=0.0014936648 T_psi=0.1690707065 sumR=0.0172254040 sumT=0.9827745960
```

Complete solution for all real diffraction orders can be obtained by using the commands total\_D\_R\_0, total\_D\_R\_90, total\_D\_R, total\_D\_T\_0, total\_D\_T\_90, total\_D\_T. For example, complete solution of all transmitted orders (TE polarization) is following

```
total D T 90
total D T 90 =
  -1.0000000000000000
                       -1.0000000000000000
                                             0.025598407906076
  -1.0000000000000000
                                             0.155028804579578
  -1.0000000000000000
                        1.0000000000000000
                                             0.025598407906077
                    0
                       -1.0000000000000000
                                             0.169070706525881
                    0
                                             0.232181942160683
                        1.0000000000000000
                                             0.169070706525886
                       -1.0000000000000000
   1.0000000000000000
                                             0.025598407906021
   1.0000000000000000
                                             0.155028804578851
   1.0000000000000000
                        1.0000000000000000
                                             0.025598407906021
```

more layers: eg. Grating (thickness 0.5)+Grating (thickness 0.5)+uniform layer

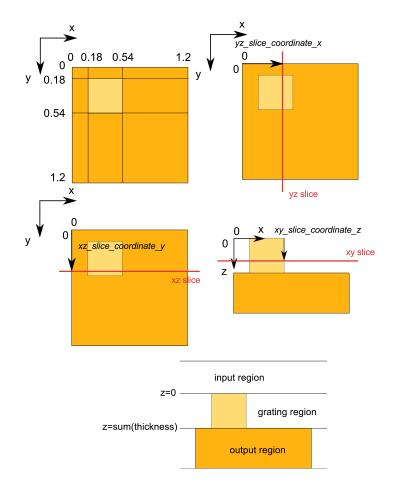
```
number_of_layers=3;
l=1; % layer 1
thickness(l)=0.5;
coordinate_x_1=1.2.*[0,0.25,0.75,1];
coordinate_y_1=1.2.*[0,0.25,0.75,1];
r_index_1=[1, 1, 1;
    1, 1.5, 1;
```

#### Field calculation

Add some text

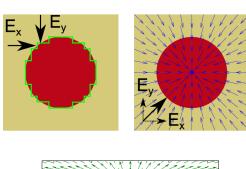
some notes on field calculation:

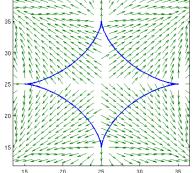
- example: main binary grating em field.m
- calculate\_field=1 → it enables field calculation
- run the main\_binary\_grating\_em\_field.m file and open (directory /em\_field) xy\_slice.m or xz\_slice.m or yz\_slice.m → change variables in slice \*.m files and run these files (all grating variables are in memory)
- field components: E<sub>x</sub>, E<sub>y</sub>, E<sub>z</sub>, H<sub>x</sub>, H<sub>y</sub>, H<sub>z</sub>
- field components can be calculated in input region, grating region, and output region
- field calculation is done for polarization angle psi0



# Normal vector method

Todo



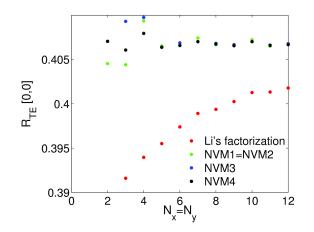


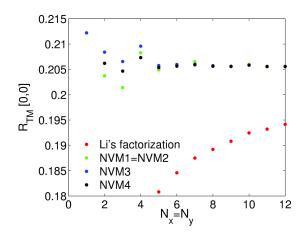
- T. Schuster, J. Ruoff, N. Kerwien, S. Rafler, W. Osten, "Normal vector method for convergence improvement using the RCWA for crossed gratings," J. Opt. Soc. Am. A 24, 2880-2890 (2007)
- R. Antoš, "Fourier factorization with complex polarization bases in modeling optics of discontinuous bi-periodic structures," Opt. Express 17, p. 7269, 2009
- P. Götz, T. Schuster, K. Frenner, S. Rafler, and W. Osten, "Normal vector method for the RCWA with automated vector field generation," Opt. Express 16, 17295-17301 (2008).
- S. Rafler, P. Goetz, M. Petschow, T. Schuster, K. Frenner, W. Osten, "Investigation of methods to set up the normal vector field for the differential method," Proc. SPIE, Vol. 6995, 2008

This example is taken from paper: R. Antos, M. Veis, S. Visnovsky, "Complex Fourier factorization method applied in modeling optical metamaterials based on 2D periodic nanostructures," Proc. SPIE, Vol. 7353 73531C-2, 2009. We suppose cylindrical holes of the diameter 2R = 200 nm, depth d = 100 nm, and square periodicity  $\Lambda = 300$  nm. We assume an incident plane wave with the wavelength  $\lambda = 500$  nm, the angle of incidence  $\theta = 60^{\circ}$ , and the conical angle  $\phi = 0^{\circ}$ . As material parameters at our spectral point we use the values of permittivity,  $\epsilon_a = 1$  for vacuum inside holes (+ incident region) and  $\epsilon_b = -2.865-3.211i$  for outside holes (+ transmission region).

Setup of the structure is saved in the test\_antos\_grating.m file. A similar input file is deeply described in the next section. This example is run from the main\_nvm.m file. In the case of cylindrical holes/rods, program RCWA-2D offers three independent setups of the normal vector fields — switch factorization\_method.

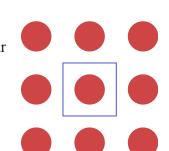
- 1) radial normal vector field
- 2) complex radial normal vector field (same as the case 1)
- 3) complex normal vector field based on complex polarization bases (Model C)
- 4) complex normal vector field based on complex polarization bases (Model C')





### Circular holes/rods - rectangular grid

Let us assume simple case of the grating ( $\Lambda_x = \Lambda_y = 1.0 \mu m$ ) consists of circular air holes (radius r=0.25  $\mu m$ , thickness t=1  $\mu m$ ) in the dielectric medium



(n=1.5). Program RCWA-2D provides two ways, how to calculate such a grating. Firstly, this grating with circular hole/rod can be discretized, then we can immediately use previous algorithm based on

Lifeng Li, "New formulation of the Fourier modal method for crossed surface-relief gratings," J. Opt. Soc. Am. A 14, 2758-2767 (1997),

or fourier coefficients of such a grating can be calculated using Bessel functions and then we have to apply an algorithm based on

Philippe Lalanne, "Improved formulation of the coupled-wave method for two-dimensional gratings," J. Opt. Soc. Am. A **14**, 1592-1598 (1997).

We first discuss the first posibility, the setup of the grating is the same as in the previous case of 2D binary grating. You have to only load rectangular\_grating.m file.

```
open grating file='rectangular grating.m';
Strucure of the rectangular grating.m file:
number of layers=1; % this parameter defines number of layers
Lambda x=\overline{1}; % [um]
Lambda y=Lambda x; % [um]
resolution dx=128; % discretization step [um]
r cylinder=0.25; % radius of the cylinder [um]
t cylinder=1; % thickness of the cylinder [um]
n cylinder=1; % refractive index of the cylinder
n layer=1.5; % refractive index of the surrounding layer
show grating mesh=2; % 1-yes, 2-no
% generation of refractive index mesh
addpath('structures scripts')
[p x,p y,mesh n mat]=rectangular grid(Lambda x,Lambda y,resolution dx,r cylinder,n
[p_x,p_y,mesn_n_max]=receasing_nesh);
_cylinder,n_layer,show_grating_mesh);
% definition of layer number 1
l=1;
nvm method(l)=1; % 1=normal vector method is on (only in this layer)
factorization method=1; % 1-radial, 2-complex radial, 3-
[N x input,N y input]=rectangular grid nvm(Lambda x,Lambda y,resolution dx,factori
zation method,r cylinder);
thickness(l)=t cylinder; % thickness of the layer
coordinate x 1=p x;
coordinate y 1=p y;
```

```
r_index_1=mesh_n_mat; % matrix of the refrative index grid
if theta=0 set-> theta0=le-6; % incident angle [degree], if theta=0
```

If you want to check the discretization of your grating, then set show\_grating\_mesh=1; and run this file. You obtain a picture like Fig. 3. Sometimes you need to add a substrate layer, e.g. with refractive index 1.5 and thickness 2 µm. Firstly, set the parameter

```
and then add something like this:
% definition of layer number 2
l=2;
thickness(l)=2; % thickness of the layer
coordinate_x_2=[0,Lambda_x];
coordinate_y_2=[0,Lambda_y];
```

number\_of\_layers=2;

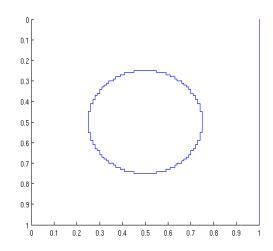


Figure 3: Discretization of a circular shape

r index 2=[1.5]; % matrix of the refrative index grid

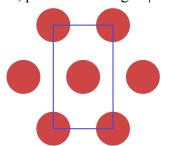
Now, we discuss the second posibility based on Bessel function and Lalanne's algorithm. Set grating=0 in the file main.m and then you can change the parameters according to your needs, in our case

```
case 1 % eliptic cylinder, rectangular grating
    number_of_layers=1;
    setup_dispersion;
    n_layer=1.5; % refractive index of the surrounding layer
    n_cylinder=1; % refractive index of the cylinder
    thickness=1; % [um]
    a_ellipse=0.25; % semi-axis [um]
    b_ellipse=0.25; % semi-axis [um]
```

Next, Lalanne's paper intoduces new convergence parametr  $\alpha$ . This parameter is a real positive number in the interval [0,1]. For this symmetrical configuration,  $\alpha$  is chosen equal to 0.5. (add more information). If we compare both algorithms, the first algorithm is faster for larger number of orders N X and more "accurate" for metallic grating.

## Circular holes/rods - hexagonal grid

Let us next consider a grating that consists of round rods arranged to have a hexagonal symmetry, as shown in Fig. 2. The grating parameters are wavelength  $\lambda$ =0.5 µm, thickness h= $\lambda$ , periods  $\Lambda_x$ = $\Lambda_y$ =2 $\lambda$ , incident angle  $\theta$ =30°, refractive index of the incident region n<sub>1</sub>=1, refractive index of the transmission region n<sub>3</sub>=sqrt(2.56), conical angle  $\varphi$ =30°, polarization angle  $\psi$ =90°, and the rods have a radius of  $\lambda$ /2.



#### Structural symmetries + adaptive spatial resolution technique

We consider square coaxial apertures in a metallic film, this example is adopted from paper: Gérard Granet and Lifeng Li. J. Opt. A: Pure Appl. Opt., Vol. 12, pp. 546-549 (2006). Parameters of the grating and calculation are following: wavelength  $\lambda$ =0.54  $\mu$ m, thickness h=0.15  $\mu$ m, periods  $\Lambda_x$ = $\Lambda_y$ =0.3  $\mu$ m, w<sub>1</sub>=0.155  $\mu$ m, w<sub>2</sub>=0.105  $\mu$ m, n<sub>2</sub>=0.22-6.71i (todo n<sub>2</sub>=0.0187-3.8069i  $\rightarrow$  it does not work properly), incident angle  $\theta$ =0°, refractive index of the incident region n<sub>1</sub>=1, refractive index of the transmission region n<sub>3</sub>=1.45.

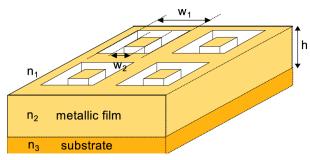


Figure 5: Definition of a structure

Let us study convergence of the zero-zero order. The structure is defined in the *coaxial apertures array.m* file

```
number of layers=1;
mu=1;
lambda=0.54;
n 1=1;
n<sup>3</sup>=1.45;
theta0=0.0;
l=1; % layer 1
thickness(l)=0.15;
Lambda x=0.3;
Lambda y=Lambda x;
w 1=0.155;
w 2=0.105;
coordinate x 1=[0,Lambda x/2-w 1/2,Lambda x/2-w
w_2/2,Lambda_x/2+w_2/2,Lambda_x/2+w_1/2,Lambda_x];
coordinate_y_1=coordinate_x_1;
n ag=0.22-6.71*1i;%0.0187+3.8069*1i; % todo correct convention
```

```
r_index_1=[n_ag, n_ag, n_ag, n_ag, n_ag;
    n_ag, 1, 1, 1, n_ag;
    n_ag, 1, n_ag, 1, n_ag;
    n_ag, 1, 1, 1, n_ag;
    n_ag, n_ag, n_ag, n_ag];
```

The convergence of the order [0,0] is shown in Fig. 6 (blue line).

Now, we will use another code:

#### http://sourceforge.net/projects/rcwa-2d/files/rcwa 2d asr sym/

This RCWA version is based on the use of the adaptive spatial resolution technique. The adaptive spatial resolution (ASR) techique is widely used in the RCWA method to reduce the Gibbs phenomenon (overshooting) around the discontinuities of the permittivity thereby to improve the convergence of the Fourier series, finally improving the accuracy of the computation result.

In certain cases, specifically when a strucure to be modeled possesses proper symmetries, both issues of memory requirements and computational time can be reduced by taking advantage of these symmetries. In our case of the RCWA method, a strucure to be modeled must possess two separate types of symmetries concurrently, structural symmetry and input wave symmetry, in order to take advantage of either.

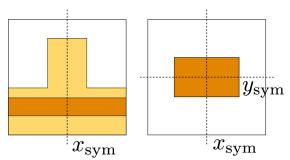


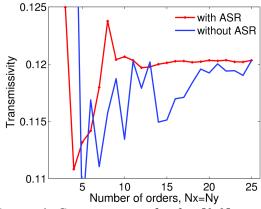
Figure 5: Schematic view of structural symmetries applied: x-axis mirror-reflection symmetry, application of both symmetries

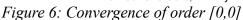
In a 2D periodic medium, there is a possibility of the occurrence of two types of one-dimensional transverse symmetries. When the material property distribution has a mirror symmetry along the x-axis of the computational window, the system is said to possess x-axis symmetry (or  $\sigma_x$  symmetry), and similarly when mirror symmetry is present about the y-axis, the system is said to possess y-axis symmetry (or  $\sigma_y$  symmetry). For a system possessing material symmetry along the x- and y-axis simultaneously, the presence of a field that is polarized along either the x- or y-axis creates also the possibility of an even further reduction in the size of the coupled wave equation eigenmode problem. The system is said to possess (x + y)-axis symmetry (or C2v symmetry).

**ASR setup:** there is a stretching coefficient ASR\_G in the interval (0, 1). It's choice can be used to tune and optimize the ASR performance. questions about choosing the proper value of parameter ASR\_G Unfortunately no scheme exists so far to predict the optimum choice of parameters ASR\_G for the ASR transformation, according to our experience, the parametr ASR\_G should be close to zero (e.g. 0.05).

Next, we set others parameters in the main.m file:

```
N X=10; % memory 8 GB: symmetry=2 \rightarrow max 20 , symmetry=1 \rightarrow max 30
N Y=N X;
ASR G=0.05; % ASR parametr, 1-no ASR, recommended value ~ 0.05
symmetry=1; % 1-yes, 2-no
symmetry switch=5; % for theta!=0 -> use y-symmetry
% 1-x_symmetry_even
% 2-x symmetry odd
% 3-y symmetry even
% 4-y symmetry odd
% 5-x y symmetry even even
% 6-x_y_symmetry_odd_odd
% 7-x y symmetry even odd
% 8-x y symmetry odd even
diffaction efficiency=[0,0]; % investigated diffraction orders (R,T)
input file='coaxial apertures array.m';
measurement=3;
```





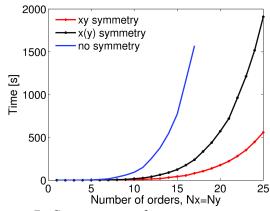


Figure 7: Comparison of computation times

The advantage of the ASR application is seen in Fig. 6 where the order [0,0] convergence with respect to the number of series-expansion terms included is shown. Also, Fig. 7 shows practically very important calculation time considerations, with a comparison of three cases: standard case with no symmetries, application of single symmetry only (x-axis), and simultaneous application of both symmetries (x and y-axis). The practical speed enhancement is clearly visible.

#### References to the ASR technique and application of structural symmetries in the RCWA method:

G. Granet, "Reformulation of the lamellar grating problem through the concept of adaptive spatial

- resolution," J. Opt. Soc. Am. A 16, p. 2510, 1999
- T. Vallius, M. Honkanen, "Reformulation of the Fourier modal method with adaptive spatial resolution: application to multilevel profiles," Opt. Express 10, p. 24, 2002
- Z. Y. Li, K. M. Ho, "Application of strucural symmetries in the plane-wave-based transfer-matrix method for 3D photonic crystal waveguides," Phys. Rev. B **68**, p. 245117, 2003
- C. Zhou and L. Li, "Formulation of Fourier modal method of symmetric crossed gratings in symmetric mountings," J. Opt. A, Pure Appl. Opt. 6, 43-50 (2004)